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Contents

ix Conference Committee хi Introduction ARTIFICIAL INTELLIGENCE IN METROLOGY 12618 02 The use of deep learning for computational optical imaging: from data driven to physics driven **(Keynote Paper)** [12618-1] Al-based solution for robust detection with optical microresonators [12618-2] 12618 03 12618 04 Thin-film thickness measurement based on spectral reflectometer using artificial neural network algorithm [12618-3] 12618 05 Al-guided numerical-aperture-controlled scatterometry for measurement of deep HAR and thin-film structures with a large depth variation [12618-4] PROCESS-INTEGRATED AND IN-SITU MEASUREMENT 12618 06 In-process powder bed monitoring with angular illumination [12618-5] 12618 08 Laser drilling controlled by laser-generated sound [12618-7] 12618 09 Sensor-guided machining of large-scale CFRP components based on resin transfer molded features [12618-8] 12618 OB Improving the accuracy and precision of OCD measurement by systematic error correction in self-interference pupil ellipsometry [12618-124] INTERFEROMETRIC TECHNIQUES AND SHEAROGRAPHY 12618 0C Simultaneous orthogonal shearography using two pairs of parallel slits and a tetra-split lens [12618-11] 12618 0D A fibre optic angle sensing tape for applications in robotics and automation [12618-12] 12618 0E Multiwavelength study of etalon effects in LCOS-based spatial light modulators [12618-13]

| 12618 OF | Three-channel space-qualified high-power pulsed fiber laser system for accurate velocity detection in bistatic configuration [12618-14] |
|----------|---|
| 12618 0G | The Nyquist criterion and its applicability in phase-stepping digital shearography [12618-15] |
| | FRINGE PROJECTION, STRUCTURED ILLUMINATION, AND PHOTOGRAMMETRY |
| 12618 OH | Thermal single-shot 3D shape measurement of transparent objects: optimization of the projected statistical LWIR pattern [12618-16] |
| 12618 01 | Identification and correction of magnification factor deviations of a telecentric fringe projection system [12618-18] |
| 12618 OJ | Metrology inside a cryostat using a cutting-edge periscope [12618-19] |
| 12618 OK | Photogrammetry for optical metrology of metal additively manufactured parts [12618-20] |
| | HIGH-RESOLUTION TOPOGRAPHY MEASUREMENT |
| 12618 OL | Microsphere-assisted microscopy: challenges and opportunities (Keynote Paper) [12618-22] |
| 12618 ON | EUV reflective coherent diffraction imaging system for wafer metrology [12618-24] |
| | TOPOGRAPHY MEASUREMENT AND PROFILOMETRY |
| 12618 OP | Indirect geometry measurement method based on confocal microscopy and fluorescent microparticles [12618-26] |
| 12618 0Q | Robust measurement of surface topography for additive manufacturing using imaging confocal microscopy [12618-27] |
| 12618 OR | Double-pass modulated differential confocal microscopy for closed-loop axial control of direct laser writing [12618-28] |
| 12618 OS | Construction of a time-domain full-field OCT for non-contact volumetric layer thickness measurement [12618-29] |
| 12618 OT | Improved 3D form profiler based on extending illumination aperture [12618-30] |
| 12618 OU | Sparse surface profile reconstruction from scattering light distributions [12618-31] |
| 12618 OV | Computational self-correction of scanning nonlinearities in optical profilometry [12618-32] |

HOLOGRAPHIC TECHNIQUES

| 12618 OW | Robust semiconductor overlay metrology with non-uniform illumination beams using digital holographic microscopy [12618-33] |
|----------|--|
| 12618 0X | Self-assembling of microlenses by pyro-electric effect for the development of compact systems [12618-34] |
| 12618 OY | Non-isoplanatic lens aberration corrections in digital holographic microscopy [12618-35] |
| 12618 OZ | Nanoscale surface topography using low-cost digital holographic microscopy [12618-75] |
| | JOINT SESSION (TRACOPTIC) II: MODELLING AND CHARACTERISATION OF QUANTITATIVE MICROSCOPES |
| 12618 12 | Compatibility analysis of profile and areal material measures [12618-39] |
| 12618 13 | Investigations on the accuracy and evaluation of the uncertainty of stitching in optical surface metrology [12618-40] |
| | MEASUREMENT OF PRECISION COMPONENTS AND OPTICAL SYSTEMS |
| 12618 15 | Improved alignment of the setup for traceable measurements of the modulation transfer function (MTF) [12618-42] |
| 12618 16 | Long-term wavelength stabilisation of widely modulated lasers [12618-43] |
| 12618 17 | Precision form measurement of biconic surfaces using scanning Fizeau interferometry [12618-44] |
| 12618 18 | Versatile modulation transfer function and direct point spread function measurement with a random target method [12618-45] |
| | |
| | SPECIAL SESSION: METROLOGY FOR AUTONOMOUS VEHICLES |
| 12618 1A | Development of a LiDAR system for low visibility conditions [12618-47] |
| 12618 1B | A lightweight laser scanner for UAV-based applications [12618-48] |
| 12618 1C | Towards image-free object detection for autonomous vehicles under harsh environmental conditions [12618-49] |

| 12618 1D | Coherence-gated digital holographic imaging through extended scattering media for autonomous driving vehicles [12618-50] |
|-----------|---|
| | SCATTERING, DIFFRACTION, AND SPECKLE TECHNIQUES |
| 12618 1E | Digital holographic microscopy with functionally-integrated waveguide illuminator (Keynote Paper) [12618-51] |
| 12618 1F | Surface roughness measurement of large areas with high spatial resolution by spectral speckle correlation [12618-52] |
| 12618 1G | Application and performance of laser speckle odometry applied to a mobile industrial robot [12618-53] |
| 12618 11 | Portable low-cost setup for outdoor implementation of dynamic speckle technique [12618-55] |
| | POLARIMETRIC, SPECTROSCOPIC, AND NONDESTRUCTIVE TECHNIQUES |
| 12618 1K | Optimal Mueller matrix imaging polarimeter in the visible band based on division-of-aperture [12618-56] |
| 12618 1L | An infrared optical sensor for quantitative inline inspection of nanocoatings on plastic products [12618-57] |
| 12618 1M | Diffraction-limited mid-infrared hyperspectral single-pixel imaging microscopy [12618-58] |
| 12618 1N | Tolerance analysis and design optimization of additively manufactured mechanical structure for a Raman spectrometer system [12618-59] |
| 12618 10 | In-line fluorescence detector for production control in robot-driven environments [12618-60] |
| | LARGE-AREA, LARGE, AND MULTISCALE MEASUREMENTS |
| 12618 1Q | Laser tracker system supporting 3D digital image correlation with dispersed measurement fields of view [12618-65] |
| 12618 1\$ | Accelerated measurement and defect characterization on large optical components [12618-63] |
| 12618 1T | An extended model for the kinematic identification of a tiltable laser plane in adaptive light-section triangulation [12618-64] |
| 12618 1U | Digital holography in a machine tool: measuring large-scale objects with micron accuracy [12618-66] |

POSTER SESSION

| 12618 1V | Forging measurement using passive stereo vision [12618-10] |
|----------|---|
| 12618 1W | Measurement analysis of optical micrometers with polygonal mirror-based laser scanners [12618-68] |
| 12618 1X | Comparative performance of high and medium resolution cameras for defect detection in carbon-fiber reinforced composites by digital shearography [12618-69] |
| 12618 1Z | Uncertainty reduction of CO ₂ laser calibration system in National Institute of Metrology (Thailand) [12618-71] |
| 12618 20 | Photoelastic and Stokes images through deep convolutional neural networks: a comparison of stress fields [12618-72] |
| 12618 21 | Optical design of refractive imaging spectrometer for semiconductor metrology [12618-73] |
| 12618 23 | Interferograms analysis for measuring the thickness of aluminum thin films [12618-77] |
| 12618 24 | Laser-based measurement system for the detection of delamination in tunnel linings [12618-78] |
| 12618 25 | OCT versus x-ray imaging in the inspection of ball grid arrays (BGAs) [12618-80] |
| 12618 26 | Thickness analysis of double-layered thin-film sample using spectral reflectometry [12618-81] |
| 12618 29 | Intensity-based dynamic speckle method for analysis of variable-rate dynamic events [12618-85] |
| 12618 2A | High NA lens assessment using self-interference incoherent digital holography [12618-86] |
| 12618 2D | Adaptive Shack-Hartmann wavefront system with extended dynamic range for lens characterization [12618-89] |
| 12618 2E | Accurate spectral transmittance measurement method of highly-opaque materials in the UV-to-IR using optical attenuators [12618-90] |
| 12618 2K | Automated assessment for grinding spots on aircraft landing gear components using robotic white light interferometry [12618-96] |
| 12618 2L | Characterization of the maximum measurable slope of optical topography measuring instruments [12618-97] |
| 12618 2N | Detection of geometrical patterns of self-assembled gold nanospheres and top-down fabricated nanostructures using coherent Fourier scatterometry [12618-99] |
| 12618 20 | Studies on micromanipulation capabilities of micro-objects and combined Raman spectroscopy based on photonic jet fiber optic [12618-100] |

| 12618 2P | Investigation to evaluate the aging condition utilizing UV radiation of carbon black filled rubber compounds as measured by ATR spectroscopy [12618-101] |
|----------|--|
| 12618 2Q | Improving the phase modulation of spatial light modulator using Shack-Hartmann wavefront sensor [12618-102] |
| 12618 2R | Conical null-screen design for evaluating fast free-form convex surfaces [12618-103] |
| 12618 2S | Shape measurement of phase objects using fringe projection technique [12618-104] |
| 12618 2T | Detection of delaminated areas in thermal barrier coatings by active infrared thermography using different heat sources [12618-105] |
| 12618 2U | Rapid surface metrology of freeform shapes using CGH interferometry [12618-106] |
| 12618 2V | Non-destructive evaluation of thermal barrier coating thickness using IR thermography in chemical removal processes [12618-107] |
| 12618 2W | Development of a liquid interferometric optical microscope (L-IOM) in phase-shift mode with standard Mirau objectives [12618-109] |
| 12618 2X | New wafer shape measurement technique for 300mm blank vertically held silicon wafers [12618-111] |
| 12618 2Y | 3D hologram optical element for angle measuring devices and sighting systems [12618-112] |
| 12618 2Z | Fabrication and test of functional panels for multimission modular satellite platform [12618-113] |
| 12618 31 | Pyro-electrohydrodynamic printing of liquid crystals [12618-115] |
| 12618 33 | Robotization of engineering equipment to improve the safety of emergency rescue operations using optical methods [12618-117] |
| 12618 34 | Block-based multi-scale image enhancement method for industrial inspection system [12618-118] |
| 12618 35 | Development of a full-field polarization interferometer for measurement of wafer surface profile [12618-119] |
| 12618 36 | Absolute flatness measurement based on shift-rotation method using the second deviation [12618-120] |